

Notice of References Cited	Application/Control No. 10/624,678	Applicant(s)/Patent Under Reexamination SUGITA ET AL.	
	Examiner Rip A. Lee	Art Unit 1713	Page 1 of 1


U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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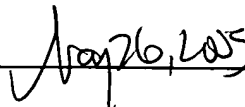
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	N	WO 01/13179 A1	02-2001	International	Yamada et al.	G03F 7/00
	O	JP 9-230596 A	09-1997	Japan	Shimokawa et al.	G03F 7/039
	P	JP 8-184966 A	07-1996	Japan	Shimokawa et al.	G03F 7/038
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NON-PATENT DOCUMENTS

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	U	JP 9-230596 (abstract and translation in English)
	V	JP 8-184966 (abstract and translation in English)
	W	JP 10-90885 (abstract and translation in English)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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 May 26, 2005